

Sensing the position of a single scatterer in opaque media using **Mutual Extinction and Transparency**



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Traditional scattering experiments are associated with sending a single beam on a target. The detailed structure of the target including the positions of all scatterers is encoded in the characteristics of the scattered waves. However, when a medium becomes opaque, usual single scattering (Fourier) approaches breaks down and only limited information is available by, e.g., diffusing wave spectroscopy. Recently, the development of multiple-beam techniques, e.g., wavefront shaping, has opened more potential in the research of opaque samples. Different from the case of a single incident wave, the interference of multiple beams gives rise to a new phenomenon called "Mutual Extinction and Transparency (MET)" [1].

Here, we conjecture that Mutual Extinction with 2 incident beams is a promising technique to detect the movement of a dipole in a sample of multiple stable dipoles. The underlying idea is that the cross-interference information of 2 beams is more sensitive to changes of the scatterer located deep within the sample than conventional scattering methods. For comparison, we perform exact calculations of the sensitivity of Mutual Extinction (from 2 beams) and the differential crosssection (from 1 beam) in response to the displacement of 1 dipole. Our numerical results confirm that Mutual Extinction is indeed more sensitive, thus, a better tool (than traditional 1-beam techniques) to locate a single scatterer inside a multiple scattering sample.



SENSITIVITY OF MET

SENSING A MOVING SCATTERER





Fig 5: Normalized deviation of Mutual Extinction & Transparency with respect to the displacement of dipole.

Normalized deviation of Mutual Extinction & Transparency:



REFERENCES

[1] A. Lagendijk, A. P. Mosk, and W. L. Vos, EPL 130, 34002 (2020) [2] A. Rates, A. Lagendijk, O. Akdemir, A. P. Mosk, and W. L. Vos, Phys. Rev. A 104, 043515 (2021)

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